

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/538,664 | | Applicant(s)/Patent Under Reexamination KEMP ET AL. | |
| | Examiner TUAN PHAM | | Art Unit 2163 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-6,108,657 | 08-2000 | Shoup et al. | 707/100 |
| * | B | US-2002/0116299 | 08-2002 | Diamond et al. | 705/28 |
| * | C | US-6,073,134 | 06-2000 | Shoup et al. | 707/100 |
| * | D | US-5,970,493 | 10-1999 | Shoup et al. | 707/100 |
| * | E | US-5,933,830 | 08-1999 | Williams, Neal Wesley | 707/100 |
| * | F | US-2002/0091681 | 07-2002 | Cras et al. | 707/3 |
| * | G | US-2002/0070971 | 06-2002 | Brown et al. | 345/775 |
| * | H | US-6,694,322 | 02-2004 | Warren et al. | 707/101 |
| * | I | US-7,333,982 | 02-2008 | Bakalash et al. | 707/5 |
| * | J | US-6,707,454 | 03-2004 | Barg et al. | 345/440 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.